


<b>Search Notes</b> 	<b>Application/Control No.</b> 10528969	<b>Applicant(s)/Patent Under Reexamination</b> IKEDA ET AL.
	<b>Examiner</b> DAQUAN ZHAO	<b>Art Unit</b> 2621

SEARCHED			
Class	Subclass	Date	Examiner
386	52, 55, 95, 125-126	6/24/2009	dz

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT; USPGPUB; USOCR; DERWENT; IBM_TDB; EPO; JPO;	6/24/2009	DZ
consult with Thai Tran for searching to 101 and 112 first	6/24/2009	dz

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
386	52, 55, 95, 125-126	8/13/2009	dz

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